

FEATURES:

- 0.5 MICRON CMOS Technology
- Typical $t_{SR(o)}$ (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- $V_{CC} = 3.3V \pm 0.3V$, Normal Range
- $V_{CC} = 2.7V$ to $3.6V$, Extended Range
- $V_{CC} = 2.5V \pm 0.2V$
- CMOS power levels ($0.4\mu W$ typ. static)
- Rail-to-Rail output swing for increased noise margin
- Available in SSOP, TSSOP, and TVSOP packages

DRIVE FEATURES:

- High Output Drivers: $\pm 24mA$
- Suitable for heavy loads

APPLICATIONS:

- 3.3V high speed systems
- 3.3V and lower voltage computing systems

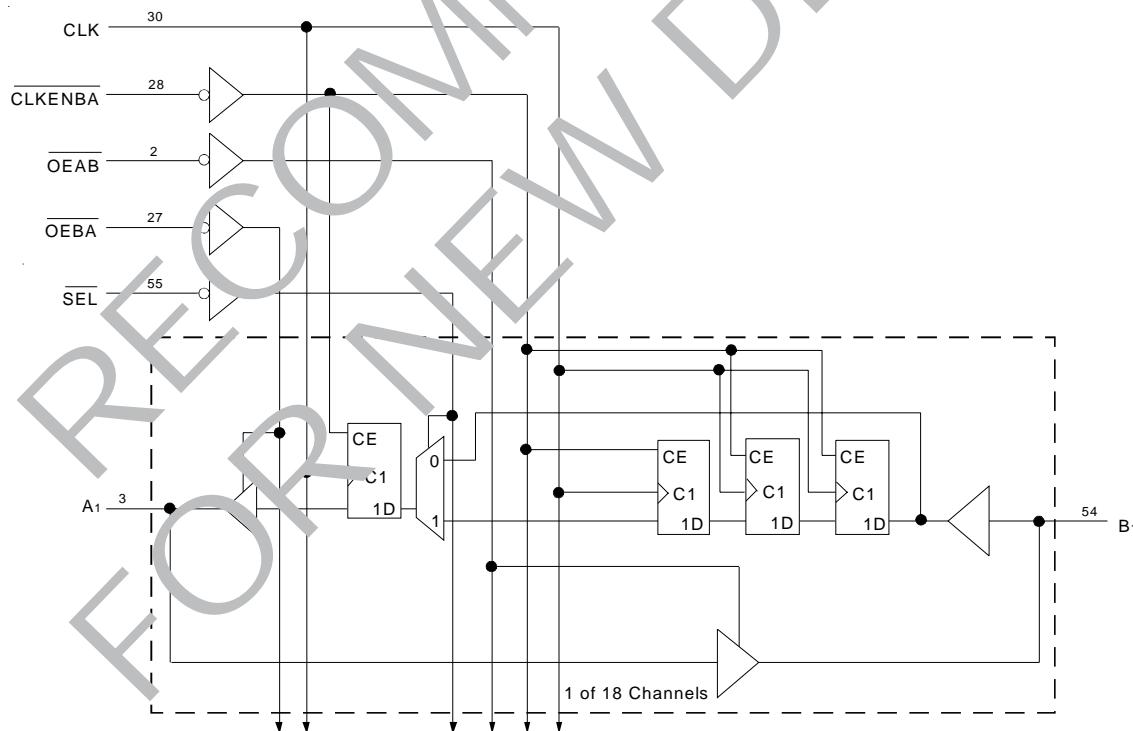
DESCRIPTION:

This 18-bit registered bus transceiver is built using advanced dual metal CMOS technology. Data flow in each direction is controlled by output-enable (\overline{OEAB} and \overline{OEBA}) and clock-enable ($CLKENBA$) inputs. For the A-to-B data flow, the data flows through a single buffer. The B-to-A data can flow through a four-stage pipeline register path, or through a single register path, depending on the state of the select (SEL) input. Data is stored in the internal registers on the low-to-high transition of the clock (CLK) input, provided that the appropriate $CLKENBA$ input is low. The B-to-A data transfer is synchronized with CLK .

The ALVCH16524 has been designed with a $\pm 24mA$ output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

The ALVCH16524 has "bus-hold" which retains the inputs' last state whenever the input bus goes to a high impedance. This prevents floating inputs and eliminates the need for pull-up/down resistors.

FUNCTIONAL BLOCK DIAGRAM

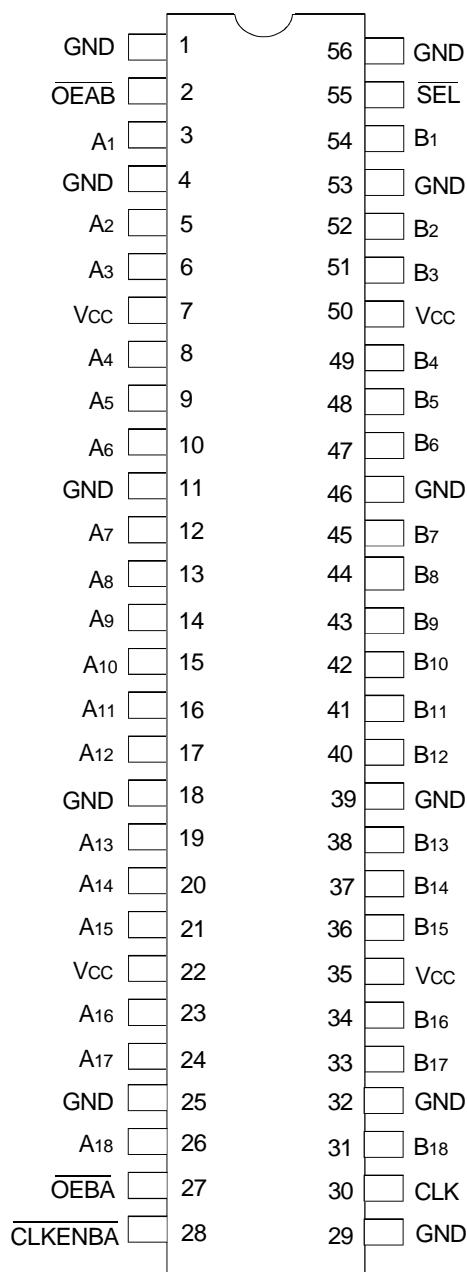


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INDUSTRIAL TEMPERATURE RANGE

APRIL 1999

PIN CONFIGURATION

SSOP/ TSSOP/ TVSOP
TOP VIEWABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max	Unit
$V_{TERM}^{(2)}$	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
$V_{TERM}^{(3)}$	Terminal Voltage with Respect to GND	-0.5 to $V_{CC}+0.5$	V
TSTG	Storage Temperature	-65 to +150	°C
I_{OUT}	DC Output Current	-50 to +50	mA
I_{IK}	Continuous Clamp Current, $V_I < 0$ or $V_I > V_{CC}$	± 50	mA
I_{OK}	Continuous Clamp Current, $V_O < 0$	-50	mA
I_{CC}	Continuous Current through each V_{CC} or GND	± 100	mA
I_{SS}			

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V_{CC} terminals.
- All terminals except V_{CC} .

CAPACITANCE ($T_A = +25^\circ C$, $F = 1.0\text{MHz}$)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C_{IN}	Input Capacitance	$V_{IN} = 0V$	5	7	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0V$	7	9	pF
$C_{I/O}$	I/O Port Capacitance	$V_{IN} = 0V$	7	9	pF

NOTE:

- As applicable to the device type.

PIN DESCRIPTION

Pin Names	Description
CLK	Clock Input
$\overline{CLKENBA}$	Clock Enable for CLK (Active LOW)
\overline{OEAB}	Output Enable for the B port (Active LOW)
\overline{OEBA}	Output Enable for the A port (Active LOW)
\overline{SEL}	Select pin for pipelined ($\overline{SEL} = 0$) / non-pipelined mode ($\overline{SEL} = 1$) in the B-to-A direction (Active LOW)
A_x	A-to-B Data Inputs or B-to-A 3-State Outputs ⁽¹⁾
B_x	B-to-A Data Inputs or A-to-B 3-State Outputs ⁽¹⁾

NOTE:

- These pins have "Bus-Hold". All other pins are standard inputs, outputs, or I/Os.

FUNCTION TABLE⁽¹⁾

A-TO-B STORAGE ($\overline{CLKENBA} = X, \overline{OEBA} = H$)				
Inputs			Output	
\overline{OEAB}	CLK	\overline{SEL}	Ax	Bx
L	X	X	L	L
L	X	X	H	H
H	X	X	X	Z

NOTES:

1. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance
 \uparrow = LOW-to-HIGH Transition
2. Output level before the indicated steady-state input conditions were established.
3. Four positive CLK edges are needed to propagate data from B to A when \overline{SEL} is LOW.

B-TO-A STORAGE ($\overline{OEBA} = L, \overline{OEAB} = H$)				
Inputs			Output	
$\overline{CLKENBA}$	CLK	\overline{SEL}	Bx	Ax
H	X	X	X	A ⁽²⁾
L	\uparrow	H	L	L
L	\uparrow	H	H	H
L	\uparrow	L	L	L ⁽³⁾
L	\uparrow	L	H	H ⁽³⁾

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: TA = -40°C to +85°C

Symbol	Parameter	Test Conditions		Min.	Typ. ⁽¹⁾	Max.	Unit
VIH	Input HIGH Voltage Level	$V_{CC} = 2.3V$ to $2.7V$		1.7	—	—	V
		$V_{CC} = 2.7V$ to $3.6V$		2	—	—	
VIL	Input LOW Voltage Level	$V_{CC} = 2.3V$ to $2.7V$		—	—	0.7	V
		$V_{CC} = 2.7V$ to $3.6V$		—	—	0.8	
I _{IH}	Input HIGH Current	$V_{CC} = 3.6V$	$V_I = V_{CC}$	—	—	± 5	μA
I _{IL}	Input LOW Current	$V_{CC} = 3.6V$	$V_I = GND$	—	—	± 5	μA
I _{OZH}	High Impedance Output Current (3-State Output pins)	$V_{CC} = 3.6V$	$V_O = V_{CC}$	—	—	± 10	μA
			$V_O = GND$	—	—	± 10	
V _{IK}	Clamp Diode Voltage	$V_{CC} = 2.3V, I_{IN} = -18mA$		—	-0.7	-1.2	V
V _H	Input Hysteresis	$V_{CC} = 3.3V$		—	100	—	mV
I _{ICL} I _{ICCH} I _{ICCZ}	Quiescent Power Supply Current	$V_{CC} = 3.6V$ $V_{IN} = GND$ or V_{CC}		—	0.1	40	μA
ΔI_{CC}	Quiescent Power Supply Current Variation	One input at $V_{CC} - 0.6V$, other inputs at V_{CC} or GND		—	—	750	μA

NOTE:

1. Typical values are at $V_{CC} = 3.3V$, $+25^\circ C$ ambient.

BUS-HOLD CHARACTERISTICS

Symbol	Parameter ⁽¹⁾	Test Conditions		Min.	Typ. ⁽²⁾	Max.	Unit
I _{BHH}	Bus-Hold Input Sustain Current	V _{CC} = 3V	V _I = 2V	-75	—	—	μA
I _{BHL}			V _I = 0.8V	75	—	—	
I _{BHH}	Bus-Hold Input Sustain Current	V _{CC} = 2.3V	V _I = 1.7V	-45	—	—	μA
I _{BHL}			V _I = 0.7V	45	—	—	
I _{BHHO}	Bus-Hold Input Overdrive Current	V _{CC} = 3.6V	V _I = 0 to 3.6V		—	—	±500
I _{BHLO}					—	—	μA

NOTES:

1. Pins with Bus-Hold are identified in the pin description.
2. Typical values are at V_{CC} = 3.3V, +25°C ambient.

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	V _{CC} = 2.3V to 3.6V	I _{OH} = -0.1mA	V _{CC} - 0.2	—	V
		V _{CC} = 2.3V	I _{OH} = -6mA	2	—	
		V _{CC} = 2.3V	I _{OH} = -12mA	1.7	—	
		V _{CC} = 2.7V		2.2	—	
		V _{CC} = 3V		2.4	—	
		V _{CC} = 3V	I _{OH} = -24mA	2	—	
V _{OL}	Output LOW Voltage	V _{CC} = 2.3V to 3.6V	I _{OL} = 0.1mA	—	0.2	V
		V _{CC} = 2.3V	I _{OL} = 6mA	—	0.4	
			I _{OL} = 12mA	—	0.7	
		V _{CC} = 2.7V	I _{OL} = 12mA	—	0.4	
		V _{CC} = 3V	I _{OL} = 24mA	—	0.55	

NOTE:

1. V_{IH} and V_{IL} must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V_{CC} range. T_A = -40°C to +85°C.

OPERATING CHARACTERISTICS, T_A = 25°C

Symbol	Parameter	Test Conditions	V _{CC} = 2.5V ± 0.2V	V _{CC} = 3.3V ± 0.3V	Unit
			Typical	Typical	
CPD	Power Dissipation Capacitance Outputs enabled	C _L = 0pF, f = 10Mhz	—	160	pF
	Power Dissipation Capacitance Outputs disabled		—	160	

SWITCHING CHARACTERISTICS⁽¹⁾

Symbol	Parameter	V _{CC} = 2.5V ± 0.2V		V _{CC} = 2.7V		V _{CC} = 3.3V ± 0.3V		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
f _{MAX}		120	—	125	—	150	—	MHz
t _{PLH}	Propagation Delay Ax to Bx	1	3.9	—	3.8	1	3.2	ns
t _{PLH}	Propagation Delay CLK to Ax	1	6.1	—	6.2	1	5.2	ns
t _{PZH}	Output Enable Time OEAB to Bx or OEBA to Ax	1	6.1	—	6.1	1	5.1	ns
t _{PHZ}	Output Disable Time OEAB to Bx or OEBA to Ax	1	6.3	—	5.4	1	4.9	ns
t _{SU}	Set-up Time, Bx data before CLK↑	1.5	—	1.2	—	1.1	—	ns
t _{SU}	Set-up Time, SEL before CLK↑	2.7	—	2.4	—	2.1	—	ns
t _{SU}	Set-up Time, CLKENBA before CLK↑	2.7	—	2.6	—	2	—	ns
t _H	Hold Time, Bx data after CLK↑	1	—	0.6	—	1.2	—	ns
t _H	Hold Time, SEL after CLK↑	0.5	—	0.2	—	0.8	—	ns
t _H	Hold Time, CLKENBA after CLK↑	0.1	—	0.1	—	0.3	—	ns
t _W	Pulse Duration, CLK HIGH or LOW	3.2	—	3.2	—	3	—	ns
t _{sk(0)}	Output Skew ⁽²⁾	—	—	—	—	—	500	ps

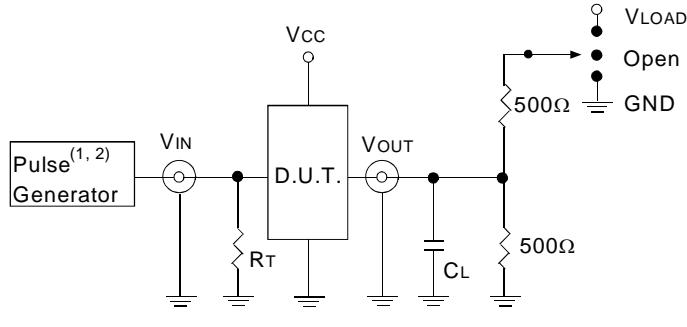
NOTES:

1. See TEST CIRCUITS AND WAVEFORMS. TA = - 40°C to + 85°C.
2. Skew between any two outputs of the same package and switching in the same direction.

TEST CIRCUITS AND WAVEFORMS

TEST CONDITIONS

Symbol	$V_{CC}^{(1)} = 3.3V \pm 0.3V$	$V_{CC}^{(1)} = 2.7V$	$V_{CC}^{(2)} = 2.5V \pm 0.2V$	Unit
V_{LOAD}	6	6	$2 \times V_{CC}$	V
V_{IH}	2.7	2.7	V_{CC}	V
V_T	1.5	1.5	$V_{CC} / 2$	V
V_{LZ}	300	300	150	mV
V_{HZ}	300	300	150	mV
C_L	50	50	30	pF



Test Circuit for All Outputs

DEFINITIONS:

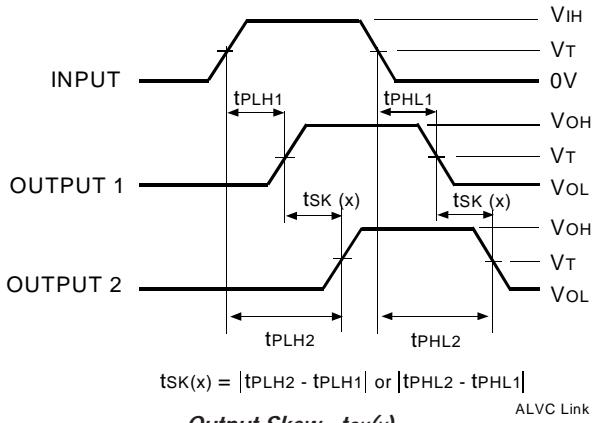
 C_L = Load capacitance: includes jig and probe capacitance. R_T = Termination resistance: should be equal to Z_{out} of the Pulse Generator.

NOTES:

1. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$.
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2\text{ns}$; $t_r \leq 2\text{ns}$.

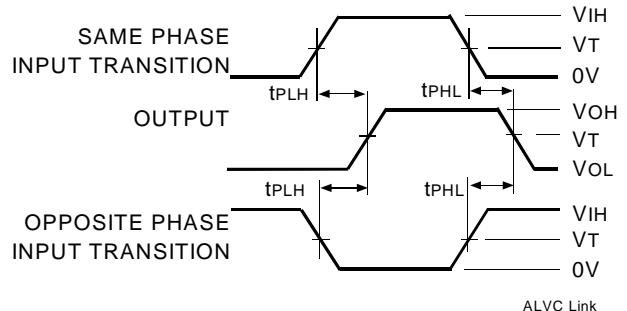
SWITCH POSITION

Test	Switch
Open Drain	
Disable Low	V_{LOAD}
Enable Low	
Disable High	GND
Enable High	
All Other Tests	Open

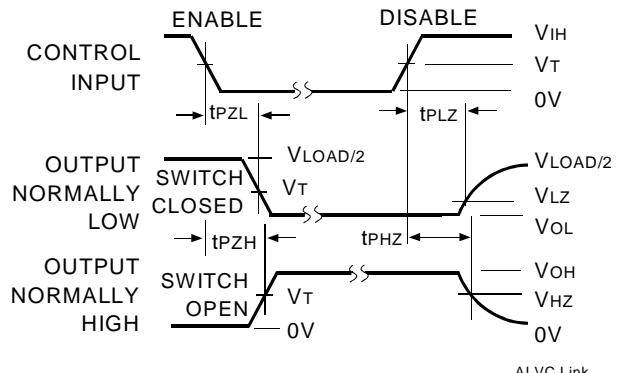
Output Skew - $tsk(x)$

NOTES:

1. For $tsk(o)$ OUTPUT1 and OUTPUT2 are any two outputs.
2. For $tsk(b)$ OUTPUT1 and OUTPUT2 are in the same bank.



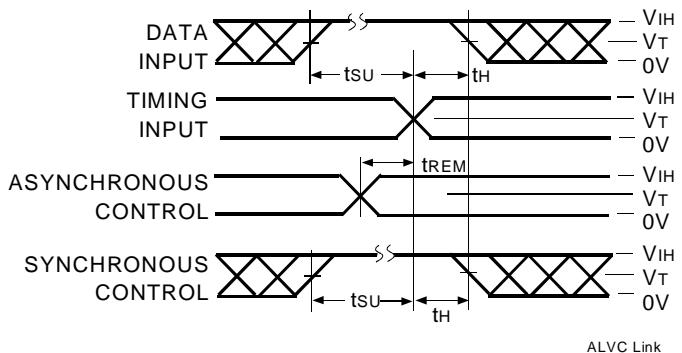
Propagation Delay



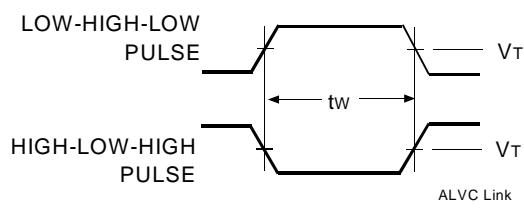
Enable and Disable Times

NOTE:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

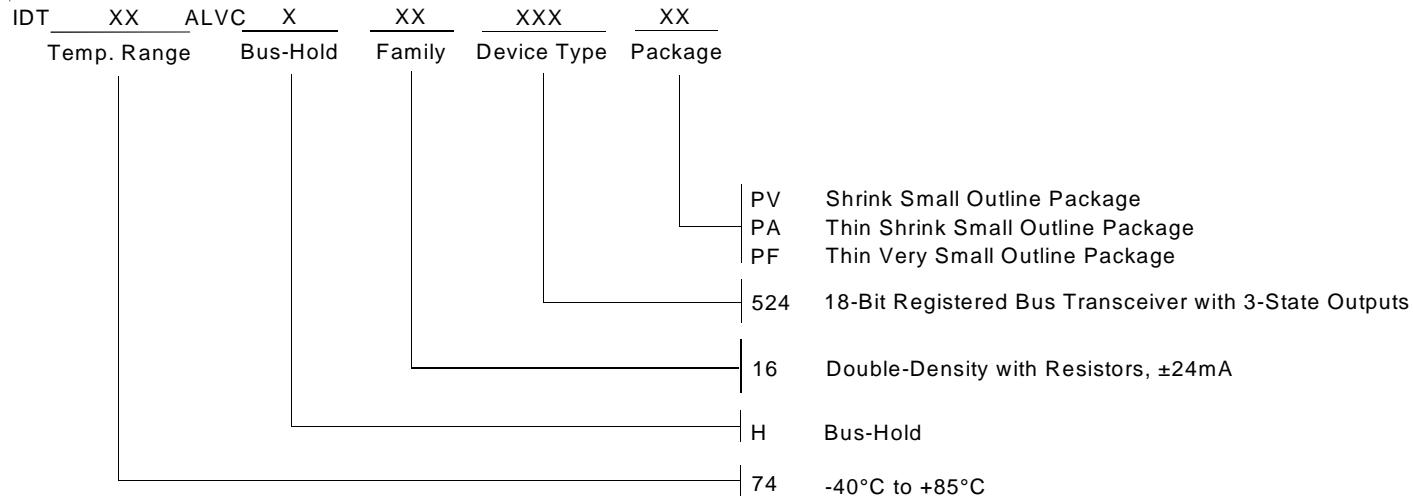


Set-up, Hold, and Release Times



Pulse Width

ORDERING INFORMATION



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